	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/767,555	CHOI ET AL.
-	Examiner	Art Unit
	Michael Krofcheck	2186

SEARCHED					
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor Name Search (PALM)	3/15/2006 _.	мск		
Plus Search	3/10/2006	мск		
EAST Search (USPAT, PGPUB, IBM_TDB, DERWENT) See attached search history	3/23/2006	мск		
711/167-169,154,104-105 365/233,194,189.02, 230.02, 230.08 Text search; See attached search history	3/23/2006	MCK		
IEEE Search, see attached search history	3/22/2006	мск		
Additional EAST search; see attached search history	9/7/2006	мск		
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